

Search Notes

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10/825,445

Examiner

Anthony Weier

Applicant(s)/Patent under
Reexamination

SHEN ET AL.

Art Unit

1761

SEARCHED

Class	Subclass	Date	Examiner
updated	previous search	3/17/2006	AW

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
426	656, 590		
	598	3/17/2006	AW

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
PGPub Text Search	3/17/2006	AW